Chip Monolithic Ceramic Capacitor for Automotive limited to Conductive Glue Mounting GCG1552C1H3R6CA01_ (0402, CH:JIS, 3.6pF, DC50V)

_: packaging code

Reference Sheet

1.Scope

This product specification is applied to Chip Monolithic Ceramic Capacitor limited to Conductive Glue Mounting Type used for Automotive Electronic equipment with conductive glue mounting.

2.MURATA Part NO. System



3. Type & Dimensions



				(Unit:mm)
(1)-1 L	(1)-2 W	(2) T	e	g
1.0±0.1	0.5±0.05	0.5±0.05	0.15 to 0.35	0.3 min.

4.Rated value

	() (e Characteristics Code):CH(JIS)	(4) Rated	(5) Nominal	(6) Capacitance	Specifications and Test Methods
F	Temp. coeff or Cap. Change	Temp. Range (Ref.Temp.)	Voltage	Capacitance	Tolerance	(Operating Temp. Range)
	0±60 ppm/°C	20 to 125 °C (20 °C)	DC 50 V	3.6 pF	±0.25 pF	-55 to 125 °C

5.Package

mark	(8) Packaging	Packaging Unit
D	∳180mm Reel PAPER W8P2	10000 pcs./Reel
W	∳180mm Reel PAPER W8P1	20000 pcs./Reel
J	∳330mm Reel PAPER W8P2	50000 pcs./Reel

Product specifications in this catalog are as of Apr.15,2016,and are subject to change or obsolescence without notice. Please consult the approval sheet before ordering.

Please read rating and !Cautions first.



■AEC-Q200 Murata Standard Specification and Test Methods

			Specifi	cation.						
No	AEC-Q200		Temperature Compensating Type	High Dielectric Type	AEC-Q200 Test Method					
1	Pre-and Post-S Electrical Test	tress			-					
2	High Temperati		The measured and observed charact specifications in the following table. No marking defects Within $\pm 2.5\%$ or $\pm 0.25pF$ (Whichever is larger) $30pFmin. : Q \ge 1000$ $20pFmay : Q \ge 400120C$	R7/L8/R9:Within ±12.5% R7/L8 : 0.05 max.	under Set th	under the same conditions as No.16. Set the capacitor for 1000±12 hours at 150±3° 24±2 hours at room temperature, then measure			s at 150±3°C. Set for	and
		I.R.	30pFmax.: Q ≧400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω • F R9 : More than 3,000MΩ or 150 Ω • F (Whichever is smaller)	R9 : 0.075max.						
α 0	Temperature C	Appearance Capacitance Change Q/D.F.	The measured and observed charact specifications in the following table. No marking defects Within $\pm 2.5\%$ or ± 0.25 pF (Whichever is larger) 30 pFmin.: Q ≥ 1000 30 pFmax.: Q $\geq 400+20$ C C: Nominal Capacitance (pF)	red and observed characteristics should satisfy thens in the following table.g defects% or ± 0.25 pFR7/L8/R9: Within $\pm 10.0\%$ r is larger)Q ≥ 1000 Q $\geq 400+20$ CR7/L8 W.V.: 25Vmin.: 0.03 maxW.V.: 16V : 0.05 max		the sam ding to th	e conditions ne four heat t	as No.1 reatmer	iig in the same manner i 6. Perform the 1000 cy tts listed in the following irature, then measure 3 125+3/-0 (for 1C/2C/3C/4C/5C/R7) 150+3/-0 (for 0C/5G/L8/R9)	cles
		I.R.	More than 10,000MΩ or 500Ω ⋅F (Whichever is smaller)		Time (min.) 15±3 1 15±3 1 • Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10 °C for one hour and then set for 24±2 hours at room temperature. Perform the initial measurement.					
4	Destructive Physical Analys	ie	No defects or abnormalities		Per E	A-469.				
5	Moisture Resist		The measured and observed characteristics should satisfy the specifications in the following table.		Fix the capacitor to the supporting jig in the same manner and under the same conditions as No.16. Apply the 24-hour heat (25 to 65°C) and humidity (80 to 98%) treatment shown below, 10 consecutive times.					
		Appearance Capacitance Change Q/D.F.	No marking defects Within ±3.0% or ±0.30pF (Whichever is larger) 30pFmin. : Q≧350 10pF and over, 30pF and below: Q≧275+5C/2 10pFmax.: Q ≧200+10C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω · F R9 : More than 3,000MΩ or 150 Ω · F (Whichever is smaller)	R7/L8/R9: Within ±12.5% R7/L8 : 0.05 max. R9 : 0.075max.	+	rature	Hum i di ty 90~98%	Hum id 80~99	^{3%} Humidity ^{80~98%} Hu	
6	Biased Humidit	Appearance Capacitance Change	The measured and observed charact specifications in the following table. No marking defects Within ±3.0% or ±0.30pF (Whichever is larger)	R7/L8/R9: Within ±12.5%	under Apply at 85± Remo	the sam the rate 3°C and ve and s	e conditions d voltage and 80 to 85% h set for 24±2 l	as No.1 d 1.3+0. numidity nours at	2/-0vdc (add 6.8kΩ resi for 1000±12 hours. room temperature, ther	ster)
		Q/D.F. I.R.	30pF and over: Q≧200 30pF and below: Q≧100+10C/3 C: Nominal Capacitance(pF) More than 1,000MΩ or 50Ω ·F (Whichever is smaller)	R7/L8:0.05 max. R9:0.075max.	The c	harge/dis	scharge curre	ent is les	ss than 50mA.	



AEC-Q200 Murata Standard Specification and Test Methods

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		T 4 14	Speci	fication.				
No	AEC-Q200	l est item	Temperature	High Dielectric Type			AEC-Q200) Test Method
7	Operational Life	2	Compensating Type The measured and observed chara	acteristics should satisfy the	Fix th	e canacitor to	the supporting iig	in the same manner and
'		5	specifications in the following table	•	Fix the capacitor to the supporting jig in the same manner and under the same conditions as No.16.			
		Appearance	No marking defects				rated voltage for 1	
		Capacitance	Within ±3.0% or ±0.30pF	R7/L8/R9: Within ±12.5%			•	7), 150±3°C(for 0C/5G/L8/R9).
		Change	(Whichever is larger)					ture, then measure.
		Q/D.F.	30pFmin. : Q≧350	R7/L8 : 0.05 max.	The c	harge/dischar	ge current is less	than 50mA.
			10pF and over, 30pF and below:	R9 : 0.075max.				
			Q≧275+5C/2		• Initia	al measureme	ent for high dielect	ric constant type.
			10pFmax.: Q ≧200+10C		Apply 200% of the rated DC voltage for one hour at the matter			
			C: Nominal Capacitance(pF)					ve and set for 24±2 hours at
		I.R.	More than 1,000MΩ or 50Ω ·F		room	temperature.	Perform initial me	asurement.
			(Whichever is smaller)					
8	External Visual		No defects or abnormalities		Vieue	linenection		
S	External visual		No defects of abnormalities		visua	I inspection		
_	DI . 1D.							
9	Physical Dimer	ISION	Within the specified dimensions		Using	calipers		
		-	<u> </u>					
0	Resistance to	Appearance	No marking defects		Per N	1IL-STD-202 N	Method 215	
	Solvents	nts Capacitance Within the specified tolerance			Solve	ent 1 : 1 part (by volume) of isor	propyl alcohol
		Change				3 parts	(by volume) of mi	neral spirits
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	Solve	ent 2 : Terpen	e defluxer	
			30pFmax.: Q ≧400+20C	W.V.: 16V : 0.035 max.			s (by volume) of w	vater
			C: Nominal Capacitance(pF)	R9 : 0.075max.		•	(, ,	ycol monomethyl ether
				1.9 . U.U/JIIIAA.				
					1	part (by volum	ne) of monoethand	blamine
		I.R.	More than 10,000M Ω or 500 Ω ${}^{\bullet}\text{F}$					
			(Whichever is smaller)					
1	Mechanical	Appearance	No marking defects		Fix th	e capacitor to	the test jig in the	same manner and under the
	Shock	Capacitance	Within the specified tolerance		same	same conditions as No.16.Three shocks in each direction should be		
		Change				ed along 3 mu	tually perpendicula	ar axes of the test specimen
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	(18 sl	hocks).		
			30pFmax.: Q ≧400+20C	W.V.: 16V : 0.035 max.	`	,	oulse should be Ha	alf-sine and should have a
			C: Nominal Capacitance(pF)	R9 : 0.075max.				nd velocity change: 4.7m/s.
			(F.)		aurat	.on .o.o.no, po	alt falder obga	na tolooky onangor minio
		I.R.	More than 10,000MΩ or 500Ω ·F	ļ				
			(Whichever is smaller)					
2	Vibration	Appearance	No defects or abnormalities		Fix th	e capacitor to	the test jig in the	same manner and under the
2	Vibration	Appearance Capacitance	No defects or abnormalities Within the specified tolerance					same manner and under the citor should be subjected to a
2	Vibration				same	conditions as	No.16. The capa	
12	Vibration	Capacitance		R7/L8 : W.V.: 25Vmin.: 0.025 max.	same simple freque	conditions as e harmonic m ency being va	No.16. The capa otion having a tota ried uniformly betw	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of
2	Vibration	Capacitance Change	Within the specified tolerance	R7/L8 : W.V.: 25Vmin.: 0.025 max. W.V.: 16V : 0.035 max.	same simple freque	conditions as e harmonic m ency being va	No.16. The capa otion having a tota ried uniformly betw	citor should be subjected to a al amplitude of 1.5mm, the
2	Vibration	Capacitance Change	Within the specified tolerance 30pFmin. : Q≧1000		same simple freque 10 an	e conditions as e harmonic m ency being va d 2000Hz. Th	No.16. The capa otion having a tota ried uniformly betw e frequency range	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of
12	Vibration	Capacitance Change	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C	W.V.: 16V : 0.035 max.	same simple freque 10 an	e conditions as e harmonic m ency being va id 2000Hz. Th n to 10Hz, sho	No.16. The capa otion having a tota ried uniformly betw a frequency range uld be traversed i	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and
2	Vibration	Capacitance Change	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C	W.V.: 16V : 0.035 max. R9 : 0.075max.	same simpl frequ 10 an returr This r	e conditions as e harmonic m ency being va id 2000Hz. Th n to 10Hz, sho	No.16. The capa otion having a tota ried uniformly betw le frequency range uld be traversed i be applied for 12	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes.
2	Vibration	Capacitance Change Q/D.F.	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF)	W.V.: 16V : 0.035 max. R9 : 0.075max.	same simpl frequ 10 an returr This r	e conditions as e harmonic me ency being va id 2000Hz. Th n to 10Hz, sho notion should	No.16. The capa otion having a tota ried uniformly betw le frequency range uld be traversed i be applied for 12	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes.
2	Vibration	Capacitance Change Q/D.F.	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω •F	W.V.: 16V : 0.035 max. R9 : 0.075max.	same simpl frequ 10 an returr This r	e conditions as e harmonic me ency being va id 2000Hz. Th n to 10Hz, sho notion should	No.16. The capa otion having a tota ried uniformly betw le frequency range uld be traversed i be applied for 12	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes.
	Vibration Thermal Shock	Capacitance Change Q/D.F.	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω •F	W.V.: 16V : 0.035 max. R9 : 0.075max.	same simpl freque 10 an returr This r perpe	conditions as e harmonic m ency being va id 2000Hz. Th n to 10Hz, sho notion should indicular direc	No.16. The capa otion having a tota ried uniformly betw e frequency range uld be traversed i be applied for 12 tions	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes.
		Capacitance Change Q/D.F.	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω •F (Whichever is smaller)	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the	same simpli freque 10 an returr This r perpe	e harmonic m ency being va id 2000Hz. Th n to 10Hz, sho motion should endicular direct	No.16. The capa otion having a tota ried uniformly bett le frequency range uld be traversed i be applied for 12 tions	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually
		Capacitance Change Q/D.F.	 Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω •F (Whichever is smaller) The measured and observed characteristic structure 	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the	same simpl freque 10 an returr This r perpe Fix th under	e harmonic me ency being va d 2000Hz. Th n to 10Hz, sho notion should endicular direct e capacitor to r the same con	No.16. The capa otion having a tota ried uniformly bett e frequency range uld be traversed i be applied for 12 tions	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and
		Capacitance Change Q/D.F.	 Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω • F (Whichever is smaller) The measured and observed chara specifications in the following table 	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the	same simpl freque 10 an returr This r perpe Fix th under accor	e harmonic me ency being va id 2000Hz. The to 10Hz, sho motion should endicular direct e capacitor to r the same con ding to the two	No.16. The capa otion having a tota ried uniformly beth e frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles
		Capacitance Change Q/D.F. I.R.	 Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω • F (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects 	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the	same simpl frequi 10 an returr This r perpe Fix th undel accor table(e harmonic me ency being va id 2000Hz. The to 10Hz, sho motion should endicular direct e capacitor to r the same con ding to the tww Maximum tran	No.16. The capa otion having a tota ried uniformly beth e frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following
		Capacitance Change Q/D.F. I.R. Appearance Capacitance	 Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω •F (Whichever is smaller) The measured and observed charaspecifications in the following table No marking defects Within ±2.5% or ±0.25pF 	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the	same simpl frequi 10 an returr This r perpe Fix th undel accor table(e harmonic me ency being va id 2000Hz. The to 10Hz, sho motion should endicular direct e capacitor to r the same con ding to the tww Maximum tran	No.16. The capa ootion having a tota ried uniformly betw he frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 second	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following econds). Set for 24±2 hours at
		Capacitance Change Q/D.F. I.R. I.R. Appearance Capacitance Change	 Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω · F (Whichever is smaller) The measured and observed charaspecifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) 	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0%	same simpl frequi 10 an returr This r perpe Fix th undel accor table(e conditions as e harmonic m ency being va d 2000Hz. Th o to 10Hz, sho notion should endicular direct e capacitor to r the same con ding to the tw Maximum trait temperature, <u>Step</u>	No.16. The capa otion having a tota ried uniformly betw le frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure 1	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following econds). Set for 24±2 hours at
		Capacitance Change Q/D.F. I.R. I.R. Appearance Capacitance Change	Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω · F (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) 30pFmin. : Q≥1000	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0% R7/L8 : W.V.: 25Vmin.: 0.025 max.	same simpl frequi 10 an returr This r perpe Fix th undel accor table(conditions as e harmonic m ency being va id 2000Hz. Th to 10Hz, sho motion should endicular direct e capacitor to the same con ding to the two Maximum tran temperature, <u>Step</u> Temp.(°C)	No.16. The capa otion having a tota ried uniformly betw e frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following econds). Set for 24±2 hours at $\frac{2}{125+3/-0}$
		Capacitance Change Q/D.F. I.R. I.R. Appearance Capacitance Change	Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω •F (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) 30pFmax.: Q≥400+20C	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0% R7/L8 : W.V.: 25Vmin.: 0.025 max. GCG21BL81H104K: 0.03 max.	same simpl frequi 10 an returr This r perpe Fix th undel accor table(conditions as e harmonic m ency being va d 2000Hz. Th to 10Hz, sho notion should endicular direc e capacitor to t the same con ding to the tw Maximum tran temperature, <u>Step</u> Temp.(°C) Time	No.16. The capa otion having a tota ried uniformly betw le frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure 1	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following sconds). Set for 24±2 hours at $\frac{2}{125+3/-0}$ (for1C/2C/3C/4C/5C/R7) 150+3/-0
		Capacitance Change Q/D.F. I.R. I.R. Appearance Capacitance Change	Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω ·F (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) 30pFmax.: Q≥400+20C	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0% R7/L8 : W.V.: 25Vmin.: 0.025 max. GCG21BL81H104K: 0.03 max. W.V.: 16V : 0.035 max.	same simpl frequi 10 an returr This r perpe Fix th undel accor table(conditions as e harmonic m ency being va id 2000Hz. Th to 10Hz, sho motion should endicular direct e capacitor to the same con ding to the two Maximum tran temperature, <u>Step</u> Temp.(°C)	No.16. The capa otion having a tota ried uniformly betw e frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure 1 -55+0/-3	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following sconds). Set for 24 \pm 2 hours at $\frac{2}{125+3/-0}$ (for1C/2C/3C/4C/5C/R7) 150+3/-0 (for 0C/5G/L8/R9)
		Appearance Change Q/D.F.	 Within the specified tolerance 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) More than 10,000MΩ or 500Ω · F (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) 30pFmin. : Q≥1000 30pFmax.: Q≥400+20C C: Nominal Capacitance(pF) 	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0% R7/L8 : W.V.: 25Vmin.: 0.025 max. GCG21BL81H104K: 0.03 max. W.V.: 16V : 0.035 max.	same simpl frequi 10 an returr This r perpe Fix th undel accor table(conditions as e harmonic m ency being va d 2000Hz. Th to 10Hz, sho notion should endicular direc e capacitor to t the same con ding to the tw Maximum tran temperature, <u>Step</u> Temp.(°C) Time	No.16. The capa otion having a tota ried uniformly betw e frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure 1 -55+0/-3	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following sconds). Set for 24 \pm 2 hours at $\frac{2}{125+3/-0}$ (for1C/2C/3C/4C/5C/R7) 150+3/-0 (for 0C/5G/L8/R9)
		Appearance Change Q/D.F.	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 10,000M Ω or $500\Omega \cdot F$ (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 10,000M Ω or $500\Omega \cdot F$	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0% R7/L8 : W.V.: 25Vmin.: 0.025 max. GCG21BL81H104K: 0.03 max. W.V.: 16V : 0.035 max.	same simpli frequu 10 an returr This r perpe accor table(room	e conditions as e harmonic m ency being va d 2000Hz. Th to 10Hz, sho notion should endicular direct e capacitor to the same con ding to the two Maximum tran temperature, Step Temp.(°C) Time (min.)	No.16. The capa otion having a tota ried uniformly betw e frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure 1 -55+0/-3	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following sconds). Set for 24 \pm 2 hours at $\frac{2}{(for 1C/2C/3C/4C/5C/R7)}$ 150+3/-0 (for 0C/5G/L8/R9) 15 \pm 3
		Appearance Change Q/D.F.	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 10,000M Ω or $500\Omega \cdot F$ (Whichever is smaller) The measured and observed chara specifications in the following table No marking defects Within ±2.5% or ±0.25pF (Whichever is larger) $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 10,000M Ω or $500\Omega \cdot F$	W.V.: 16V : 0.035 max. R9 : 0.075max. acteristics should satisfy the R7/L8/R9: Within ±10.0% R7/L8 : W.V.: 25Vmin.: 0.025 max. GCG21BL81H104K: 0.03 max. W.V.: 16V : 0.035 max.	same simpli frequu 10 an returr This r perpe accor table(room	conditions as e harmonic m ency being va id 2000Hz. Th to 10Hz, sho notion should endicular direct e capacitor to the same con ding to the tw Maximum tran temperature, Step Temp.(°C) Time (min.)	No.16. The capa otion having a tota ried uniformly betw are frequency range uld be traversed i be applied for 12 tions the supporting jig nditions as No.16. o heat treatments nsfer time is 20 set then measure 1 -55+0/-3 15±3	citor should be subjected to a al amplitude of 1.5mm, the ween the approximate limits of e, from 10 to 2000Hz and n approximately 20 minutes. cycle in each 3 mutually in the same manner and Perform the 300 cycles listed in the following sconds). Set for 24 \pm 2 hours at $\frac{2}{(for 1C/2C/3C/4C/5C/R7)}$ 150+3/-0 (for 0C/5G/L8/R9) 15 \pm 3
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■AEC-Q200 Murata Standard Specification and Test Methods

			Specifi	cation.	
No	AEC-Q2	200 Test Item	Temperature		AEC-Q200 Test Method
		1	Compensating Type	High Dielectric Type	
14	ESD	Appearance	No marking defects		Per AEC-Q200-002
		Capacitance	Within the specified tolerance		
		Change		1	-
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	
			30pFmax.: Q ≧400+20C	W.V.: 16V :0.035 max.	
			C: Nominal Capacitance(pF)	R9 : 0.075max.	
		I.R.	More than 10,000MΩ or 500Ω · F		
			(Whichever is smaller)		
15	Electrical	Appearance	No defects or abnormalities		Visual inspection.
	Chatacteri- zation	Capacitance Change	Within the specified tolerance		The capacitance/Q/D.F. should be measured at 20°C(for 0C/1C/2C/3C/4C) 25°C(for 5C/5G/R7/L8/R9) at the frequency and voltage shown in the table
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	
			30pFmax.: Q ≧400+20C	W.V.: 16V : 0.035 max.	Char. ΔC,5G (more than 1000pF)
			C: Nominal Capacitance(pF)	R9 : 0.075max.	Item (1000 pF and below) $R7,R9,L8(C \le 10 \mu F)$
			er rennar expressioner(pr)		Frequency 1±0.1MHz 1±0.1kHz
					Voltage 0.5 to 5Vrms 1±0.2Vrms
		I.R. 25°C	More than 100.000MΩ or 1000Ω+F	More than 10,000MΩ or 500Ω • F	The insulation resistance should be measured with a DC voltage not
			(Whichever is smaller)	(Whichever is smaller)	exceeding the rated voltage at 25°C and 125°C(for 1C/2C/3C/4C/5C/R7)/
			, , , , , , , , , , , , , , , , , , ,	,	150°C(for 0C/5G/L8/R9) within 2 minutes of charging.
		I.R. 125°C	More than 10,000MΩ or 100Ω • F	More than 1,000MΩ or 10Ω•F	
			(Whichever is smaller)	(Whichever is smaller)	
		I.R. 150°C	More than 10,000MΩ or 100Ω • F	More than 1,000MΩ or 1Ω•F	
			(Whichever is smaller)	(Whichever is smaller)	
		Dielectric	No failure	•	No failure should be observed when 250% of the rated voltage is
		Strength			applied between the terminations for 1 to 5 seconds, provided the
					charge/ discharge current is less than 50mA.
16	Terminal Strength	Appearance	No marking defects		Mount the capacitor on the test jig in Fig.1 using a conductive glue (HEREAUS"PC3000").
	g	Capacitance	Within specified tolerance		The conductive glue is hardened at 140°C for 30minites.
		Change Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	Then apply *shear tension in parallel with the test jig for 60sec.
		G/D.1 .	30pFmax.: Q ≧400+20C	W.V.: 16V: 0.035max.	*Show in the table 1
			C: Nominal Capacitance(pF)	R9 : 0.075max.	
			e. Herminal expressioner(pr)		Ag Pd electrode Alumina
		I.R.	More than 10,000MΩ or 500Ω ·F		
			(Whichever is smaller)		
				e Tension	
			GCG15 GCG18	2. ON 2. 7N	
			GCG21	4. 9N	Type a b c
			GCG31	6. 9N	GCG15 0.4 1.5 0.5
			GCG32	12.6N	GCG18 1.0 3.0 1.2
			Table. 1		GCG21 1.2 4.0 1.65
					GCG31 2.2 5.0 2.0 GCG32 2.2 5.0 2.9
					Fig. 1 (in mm)

AEC-Q200 Murata Standard Specification and Test Methods

			Spec	ification.	
No	AEC-Q200	Test Item	Temperature Compensating Type	High Dielectric Type	AEC-Q200 Test Method
17	Beam Load Test		Destruction value should be excee < Chip L dimension : 2.5mm max. : Chip thickness : Chip thickness < Chip L dimension : 3.2mm mim. : Chip thickness <	> > 0.5mm rank : 20N ≦0.5mm rank : 8N	Place the capacitor in the beam load fixture as Fig 2. Apply a force. < Chip Length : 2.5mm max. > Iron Board < Chip Length : 3.2mm min. > Iron Board Fig.2 Speed supplied the Stress Load : 0.5mm / sec.
18	Capacitance Temperature Characteristics	Capacitance Change	Within the specified tolerance. (Table A)	R7 : Within $\pm 15\%$ (-55°C to +125°C) L8 : Within $\pm 15\%$ (-55°C to +125°C) Within +15/-40% (+125°C to +150°C) R9 : Within $\pm 15\%$ (-55°C to +150°C)	The capacitance change should be measured after 5 min. at each specified temperature stage. (1)Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step1 through 5 (Δ C: +25°C to +125°C, 5G:+25°C to +150°C other temp. coifficient.:+25°C to +85°C) the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A-1. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the step
		Temperature Coefficient Capacitance Drift	Within the specified tolerance. (Table A) Within ±0.2% or ±0.05 pF (Whichever is larger.)		1,3 and 5 by the cap value in step 3. 1,3 and 5 by the cap value in step 3. $ \begin{array}{r} \hline Step & Temp. (^{\circ}C) \\ \hline 1 & 25\pm2 \\ \hline 2 & -55\pm3 \\ \hline 3 & 25\pm2 \\ \hline 4 & 125\pm3(for \ 1C/2C/3C/4C/5C/R7) \\ \hline 150\pm3(for \ 0C/5G/L8/R9) \\ \hline 5 & 25\pm2 \\ \hline \end{array} $ (2) High Dielectric Constant Type The ranges of capacitance change compared with the above 25°C value over the temperature ranges shown in the table should be within the specified ranges. Initial measurement for high dielectric constant type. Perform a heat treatment at 150+0/-10°C for one hour and then set for 24\pm2 hours at room temperature. Perform the initial measurement.

Table A

Char.		Capacitance Change from 20°C (%)							
	Nominal Values (ppm/°C)*1		-55 -25		5	-10			
	(ppm/ C) T	Max.	Min.	Max.	Min.	Max. Min.			
1C	0±30	0.54	-0.23	0.33	-0.14	0.22	-0.09		
0C/2C	0±60	0.82	-0.45	0.49	-0.27	0.33	-0.18		
3C	0±120	1.37	-0.90	0.82	-0.54	0.55	-0.36		
4C	0±250	2.56	-1.88	1.54	-1.13	1.02	-0.75		

*1 Nominal values denote the temperature coefficient with a range of 20 $^\circ\!\mathrm{C}$ to 125 $^\circ\!\mathrm{C}.$

(0C: temperature coefficient with a range of 20°C to 150°C.)

Char.	Nominal Values		Capa	citance Char	ge from 25°C (%)			
		-5	55	-9	30	-10		
	(ppm/°C) *2	Max.	Min.	Max.	Min.	Max.	Min.	
5C/5G	0± 30	0.58	-0.24	0.40	-0.17	0.25	-0.11	

*2: Nominal values denote the temperature coefficient within a range of 25°C to 125°C(for Δ C)/ 150°C(for 5G).



1.Tape Carrier Packaging(Packaging Code:D/E/W/F/L/J/K)

1.1 Minimum Quantity(pcs./reel)

			φ180mm reel		φ330m	nm reel
Ту	/pe	Paper	[.] Tape	Plastic Tape	Paper Tape	Plastic Tape
		Code:D/E	Code:D/E Code:W Code:L		Code:J/ F	Code:K
GCG15	5	10000	20000	/	50000	/
60615	5	(W8P2)	(W8P1)		(W8P2)	
GCG18	8	4000			10000	
	6	4000			10000	
GCG21	9	4000			10000	
	В			3000		10000
GCG31	М			3000		10000
60631	С			2000		6000
GCG32	D			1000		4000
60632	E			1000		4000

1.2 Dimensions of Tape

(1)GCG15(W8P2 CODE:D/E/J/F) <Paper Tape>



(2)GCG15(W8P1 CODE:W) <Paper Tape> 1.75±0.1 1.0±0.05 ϕ 1. 5 $^{+0.1}_{-0}$ \leftrightarrow 3.5±0.05 8.0±0.3 -+--÷ \leftrightarrow 1.0 ± 0.05 1_tſ Dimensions A *3 B *3 Туре t W L GCG15 ±0.05 0.65 1.15 0.8 max. 5 ±0.1 *3 Nominal value

(in:mm)

(in:mm)

Package GCG Type

(3)GCG18/21 <Paper Tape>



Туре		Dimer Tolerand	nsions ce(Chip)	TDimensions	А	В	t
.,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		L	W	(Chip)		_	
GCG18	8	±0.2	±0.1	0.8±0.1	1.05±0.10	1.85±0.10	
GCG21	6	+0.2	+0.0	0.6±0.1	1 55 ± 0.45	±0.15 2.30±0.15	
60621	9	±0.3	±0.2	0.85±0.1	1.55±0.15	2.30±0.15	

(4)GCG21/31/32 <Plastic Tape>

D

Е

 ± 0.4

 ± 0.3

GCG32



 2.0 ± 0.3

 2.5 ± 0.3

 2.80 ± 0.20

 3.50 ± 0.20

3.0 max.

3.7 max.

(in:mm)





- 1.3 Tapes for capacitors are wound clockwise shown in Fig.3.
 - (The sprocket holes are to the right as the tape is pulled toward the user.)
- 1.4 Part of the leader and part of the vacant section are attached as follows.



- 1.5 Accumulate pitch : 10 of sprocket holes pitch = 40±0.3mm
- 1.6 Chip in the tape is enclosed by top tape and bottom tape as shown in Fig.1.
- 1.7 The top tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 1.8 There are no jointing for top tape and bottom tape.
- 1.9 There are no fuzz in the cavity.
- 1.10 Break down force of top tape : 5N min. Break down force of bottom tape : 5N min. (Only a bottom tape existence)
- 1.11 Reel is made by resin and appeaser and dimension is shown in Fig 2. There are possibly to change the material and dimension due to some impairment.
- 1.12 Peeling off force : 0.1N to 0.6N in the direction as shown below.



1.13 Label that show the customer parts number, our parts number, our company name, inspection number and quantity, will be put in outside of reel.

Limitation of Applications

Please contact us before using our products for the applications listed below which require especially high reliability for the prevention of defects which might directly cause damage to the third party's life, body or property.

①Aircraft equipment
 ②Aerospace equipment
 ③Undersea equipment
 ④Power plant control equipment
 ⑤Medical equipment
 ⑥Transportation equipment(vehicles,trains,ships,etc.)
 ⑦Traffic signal equipment
 ⑧Data-processing equipment
 ⑩Application of similar complexity and/or reliability requirements to the applications listed in the above.

Storage and Operation condition

- 1. If store the chip monolithic ceramic capacitors in an atmosphere consisting of high temperature or humidity, sulfur or chlorine gases, contaminants attach to the surface of external electrode, and bondability with conductive glue may deteriorate. Do not store the capacitors in an atmosphere consisting of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammoria gas, etc.). Storage environment must be at room temperature of +5°C to +40°C and a relative humidity of 20% to 70%, and use the product within six months. In case of packaging, do not open the last wrappend, polyethylene bag, till just before using. After unpacking, immediately reseal, or store in a desiccator containing a desiccant.
- 2. Due to moisture condensation caused by rapid humidity changes, or the photochemical change caused by direct sunlight on the terminal electrodes and/or the resin/epoxy coatings, the bondability with conductive glue and electrical performance may deteriorate. Do not store capacitors under direct sunlight or in high humidity conditions.
- 3. This product is chip monolithic ceramic capacitor limited to conductive glue mounting. Do not apply mounting method other than conductive glue. Flow or reflow soldering can result in a lack of adhesive strength on the outer electrode by poor wettability, which may result in chips breaking loose from the PCB.

Rating

1.Temperature Dependent Characteristics

- 1. The electrical characteristics of the capacitor can change with temperature.
- 1-1. For capacitors having larger temperature dependency, the capacitance may change with temperature changes. The following actions are recommended in order to ensure suitable capacitance values.
- (1) Select a suitable capacitance for the operating temperature range.
- (2) The capacitance may change within the rated temperature. When you use a high dielectric constant type capacitor in a circuit that needs a tight (narrow) capacitance tolerance (e.g., a time-constant circuit), please carefully consider the temperature characteristics, and carefully confirm the various characteristics in actual use conditions and the actual system.



[Example of Temperature Caracteristics X7R(R7)]

Sample: 0.1µF, Rated Voltage 50VDC





2.Measurement of Capacitance

- 1. Measure capacitance with the voltage and frequency specified in the product specifications.
- 1-1. The output voltage of the measuring equipment may decrease occasionally when capacitance is high. Please confirm whether a prescribed measured voltage is impressed to the capacitor.
- 1-2. The capacitance values of high dielectric constant type capacitors change depending on the AC voltage applied. Please consider the AC voltage characteristics when selecting a capacitor to be used in a AC circuit.

3.Applied Voltage

- 1. Do not apply a voltage to the capacitor that exceeds the rated voltage as called out in the specifications.
- 1-1. Applied voltage between the terminals of a capacitor shall be less than or equal to the rated voltage.
- (1) When AC voltage is superimposed on DC voltage, the zero-to-peak voltage shall not exceed the rated DC voltage. When AC voltage or pulse voltage is applied, the peak-to-peak voltage shall not exceed the rated DC voltage.
- (2) Abnormal voltages (surge voltage, static electricity, pulse voltage, etc.) shall not exceed the rated DC voltage.



(E : Maximum possible applied voltage.)

1-2. Influence of over voltage

Over voltage that is applied to the capacitor may result in an electrical short circuit caused by the breakdown of the internal dielectric layers .

The time duration until breakdown depends on the applied voltage and the ambient temperature.

4.Type of Applied Voltage and Self-heating Temperature

1.Confirm the operating conditions to make sure that no large current is flowing into the capacitor due to the continuous application of an AC voltage or pulse voltage.

When a DC rated voltage product is used in an AC voltage circuit or a pulse voltage circuit, the AC current or pulse current will flow into the capacitor; therefore check the self-heating condition.

Please confirm the surface temperature of the capacitor so that the temperature remains within the upper limits of the operating temperature, including the rise in temperature due to self-heating. When the capacitor is used with a high-frequency voltage or pulse voltage, heat may be generated by dielectric loss.

<Applicable to Rated Voltage of less than 100VDC>

 1-1. The load should be contained to the level such that when measuring at atmospheric temperature of 25°C, the product's self-heating remains below 20°C and the surface temperature of the capacitor in the actual circuit remains within the maximum operating temperature. $\label{eq:constraint} \begin{array}{l} [Example of Temperature Rise (Heat Generation) in Chip \\ Monolithic Ceramic Capacitors in Contrast to Ripple Current] \\ Sample: R(R1) characteristics 10 \mu F, Rated voltage: DC10V \end{array}$



muRata ∆Caution

5. DC Voltage and AC Voltage Characteristic

- The capacitance value of a high dielectric constant type capacitor changes depending on the DC voltage applied. Please consider the DC voltage characteristics when a capacitor is selected for use in a DC circuit.
- 1-1. The capacitance of ceramic capacitors may change sharply depending on the applied voltage. (See figure) Please confirm the following in order to secure the capacitance.
- (1) Determine whether the capacitance change caused by the applied voltage is within the allowed range .
- (2) In the DC voltage characteristics, the rate of capacitance change becomes larger as voltage increases, even if the applied voltage is below the rated voltage. When a high dielectric constant type capacitor is used in a circuit that requires a tight (narrow) capacitance tolerance (e.g., a time constant circuit), please carefully consider the voltage characteristics, and confirm the various characteristics in the actual operating conditions of the system.
- The capacitance values of high dielectric constant type capacitors changes depending on the AC voltage applied.
 Please consider the AC voltage characteristics when selecting a capacitor to be used in a AC circuit.

6. Capacitance Aging

 The high dielectric constant type capacitors have an Aging characteristic in which the capacitance value decreases with the passage of time. When you use a high dielectric constant type capacitors in a circuit that needs a tight (narrow) capacitance tolerance (e.g., a time-constant circuit), please carefully consider the characteristics of these capacitors, such as their aging, voltage, and temperature characteristics. In addition, check capacitors using your actual appliances at the intended environment and operating conditions.

7.Vibration and Shock

- 1. Please confirm the kind of vibration and/or shock, its condition, and any generation of resonance. Please mount the capacitor so as not to generate resonance, and do not allow any impact on the terminals.
- Mechanical shock due to being dropped may cause damage or a crack in the dielectric material of the capacitor. Do not use a dropped capacitor because the quality and reliability may be deteriorated.
- 3. When printed circuit boards are piled up or handled, the corner of another printed circuit board should not be allowed to hit the capacitor in order to avoid a crack or other damage to the capacitor.







[Example of Change Over Time (Aging characteristics)]





Mounting

1. Selection of Conductive Adhesive, Mounting Process, and Bonding Strength

1. The acuired bonding strength may change greatly depending on the conductive adhesive to be used. Be sure to confirming the desired performance can be acquired in the assumed monting process with the conductive adhesive to be used.

2.Maintenance of the Mounting (pick and place) Machine

- 1. Make sure that the following excessive forces are not applied to the capacitors.
- 1-1. In mounting the capacitors on the printed circuit board, any bending force against them shall be kept to a minimum to prevent them from any damage or cracking. Please take into account the following precautions and recommendations for use in your process.
 - (1) Adjust the lowest position of the pickup nozzle so as not to bend the printed circuit board.
 - (2) Adjust the nozzle pressure within a static load of 1N to 3N during mounting.



2.Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving smoothly. This imposes greater force upon the chip during mounting, causing cracked chips. Also, the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked and replaced periodically.

3.Moisture proof

1. To prevent the silver electrode migration, keep parts under low moisture condition with resin coating and the equivalent.

4.Coating

 A crack may be caused in the capacitor due to the stress of the thermal contraction of the resin during curing process. The stress is affected by the amount of resin and curing contraction. Select a resin with low curing contraction. The difference in the thermal expansion coefficient between a coating resin or a molding resin and the capacitor may cause the destruction and deterioration of the capacitor such as a crack or peeling, and lead to the deterioration of insulation resistance or dielectric breakdown.

Select a resin for which the thermal expansion coefficient is as close to that of the capacitor as possible. A silicone resin can be used as an under-coating to buffer against the stress.

- Select a resin that is less hygroscopic. Using hygroscopic resins under high humidity conditions may cause the deterioration of the insulation resistance of a capacitor. An epoxy resin can be used as a less hygroscopic resin.
- 3. The halogen system substance and organic acid are included in coating material, and a chip corrodes by the kind of Coating material. Do not use strong acid type.

Others

1. Under Operation of Equipment

- 1-1. Do not touch a capacitor directly with bare hands during operation in order to avoid the danger of an electric shock.
- 1-2. Do not allow the terminals of a capacitor to come in contact with any conductive objects (short-circuit). Do not expose a capacitor to a conductive liquid, inducing any acid or alkali solutions.
- 1-3. Confirm the environment in which the equipment will operate is under the specified conditions.
 - Do not use the equipment under the following environments.
 - (1) Being spattered with water or oil.
 - (2) Being exposed to direct sunlight.
 - (3) Being exposed to ozone, ultraviolet rays, or radiation.
 - (4) Being exposed to toxic gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
 - (5) Any vibrations or mechanical shocks exceeding the specified limits.
 - (6) Moisture condensing environments.
- 1-4. Use damp proof countermeasures if using under any conditions that can cause condensation.

2. Others

- 2-1. In an Emergency
- (1) If the equipment should generate smoke, fire, or smell, immediately turn off or unplug the equipment. If the equipment is not turned off or unplugged, the hazards may be worsened by supplying continuous power.
- (2) In this type of situation, do not allow face and hands to come in contact with the capacitor or burns may be caused by the capacitor's high temperature.
- 2-2. Disposal of waste

When capacitors are disposed of, they must be burned or buried by an industrial waste vendor with the appropriate licenses.

- 2-3. Circuit Design
- (1) Addition of Fail Safe Function

Capacitors that are cracked by dropping or bending of the board may cause deterioration of the insulation resistance, and result in a short. If the circuit being used may cause an electrical shock, smoke or fire when a capacitor is shorted, be sure to install fail-safe functions, such as a fuse, to prevent secondary accidents.

(2) This series are not safety standard certified products.

2-4. Remarks

Failure to follow the cautions may result, worst case, in a short circuit and smoking when the product is used. The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions.

Select optimum conditions for operation as they determine the reliability of the product after assembly. The data herein are given in typical values, not guaranteed ratings.

muRata Notice

Rating

1.Operating Temperature

- 1. The operating temperature limit depends on the capacitor.
- 1-1. Do not apply temperatures exceeding the maximum operating temperature. It is necessary to select a capacitor with a suitable rated temperature that will cover the operating temperature range. It is also necessary to consider the temperature distribution in equipment and the seasonal temperature variable factor.
- 1-2. Consider the self-heating factor of the capacitor The surface temperature of the capacitor shall not exceed the maximum operating temperature including self-heating.

2.Atmosphere Surroundings (gaseous and liquid)

- 1. Restriction on the operating environment of capacitors.
- 1-1. Capacitors, when used in the above, unsuitable, operating environments may deteriorate due to the corrosion of the terminations and the penetration of moisture into the capacitor.
- 1-2. The same phenomenon as the above may occur when the electrodes or terminals of the capacitor are subject to moisture condensation.
- 1-3. The deterioration of characteristics and insulation resistance due to the oxidization or corrosion of terminal electrodes may result in breakdown when the capacitor is exposed to corrosive or volatile gases or solvents for long periods of time.

3.Piezo-electric Phenomenon

1. When using high dielectric constant type capacitors in AC or pulse circuits, the capacitor itself vibrates at specific frequencies and noise may be generated. Moreover, when the mechanical vibration or shock is added to capacitor, noise may occur.

Others

1.Transportation

- 1. The performance of a capacitor may be affected by the conditions during transportation.
- 1-1. The capacitors shall be protected against excessive temperature, humidity and mechanical force during transportation.
 - (1) Climatic condition
 - low air temperature : -40°C
 - change of temperature air/air : -25°C/+25°C
 - · low air pressure : 30 kPa
 - · change of air pressure : 6 kPa/min.

(2) Mechanical condition

Transportation shall be done in such a way that the boxes are not deformed and forces are not directly passed on to the inner packaging.

- 1-2. Do not apply excessive vibration, shock, or pressure to the capacitor.
 - (1) When excessive mechanical shock or pressure is applied to a capacitor, chipping or cracking may occur in the ceramic body of the capacitor.
 - (2) When the sharp edge of an air driver, tweezers, a chassis, etc. impacts strongly on the surface of the capacitor, the capacitor may crack and short-circuit.
- 1-3. Do not use a capacitor to which excessive shock was applied by dropping etc. A capacitor dropped accidentally during processing may be damaged.

2.Characteristics Evaluation in the Actual System

- 1. Evaluate the capacitor in the actual system, to confirm that there is no problem with the performance and specification values in a finished product before using.
- 2. Since a voltage dependency and temperature dependency exists in the capacitance of high dielectric type ceramic capacitors, the capacitance may change depending on the operating conditions in the actual system. Therefore, be sure to evaluate the various characteristics, such as the leakage current and noise absorptivity, which will affect the capacitance value of the capacitor.
- 3. In addition, voltages exceeding the predetermined surge may be applied to the capacitor by the inductance in the actual system. Evaluate the surge resistance in the actual system as required.

- 1.Please make sure that your product has been evaluated in view of your specifications with our product being mounted to your product.
- 2. Your are requested not to use our product deviating from this product specification.
- 3.We consider it not appropriate to include any terms and conditions with regard to the business transaction in the product specifications, drawings or other technical documents. Therefore, if your technical documents as above include such terms and conditions such as warranty clause, product liability clause, or intellectual property infringement liability clause, they will be deemed to be invalid.